

Chapter 6-2. Carrier injection under forward bias

Last class, we established the excess minority carrier concentration profile under biased conditions.

The excess minority carrier concentration **at the edge of the depletion layer** will increase under forward biased condition. The minimum carrier concentration decreases exponentially with distance from the depletion layer edge.

$$\Delta n_p(x'') = \Delta n_p(0) e^{-\frac{x''}{L_n}}$$

$$\Delta p_n(x') = \Delta p_n(0) e^{-\frac{x'}{L_p}}$$

Carrier injection under forward bias

At equilibrium, # of holes *diffusing to n-side* equals # of holes *drifting from n-side*. When we apply external forward voltage, V_A , holes diffusing (injection) to n-side from p-side increases exponentially. This increases the hole concentration at the edge of the depletion layer on n-side.

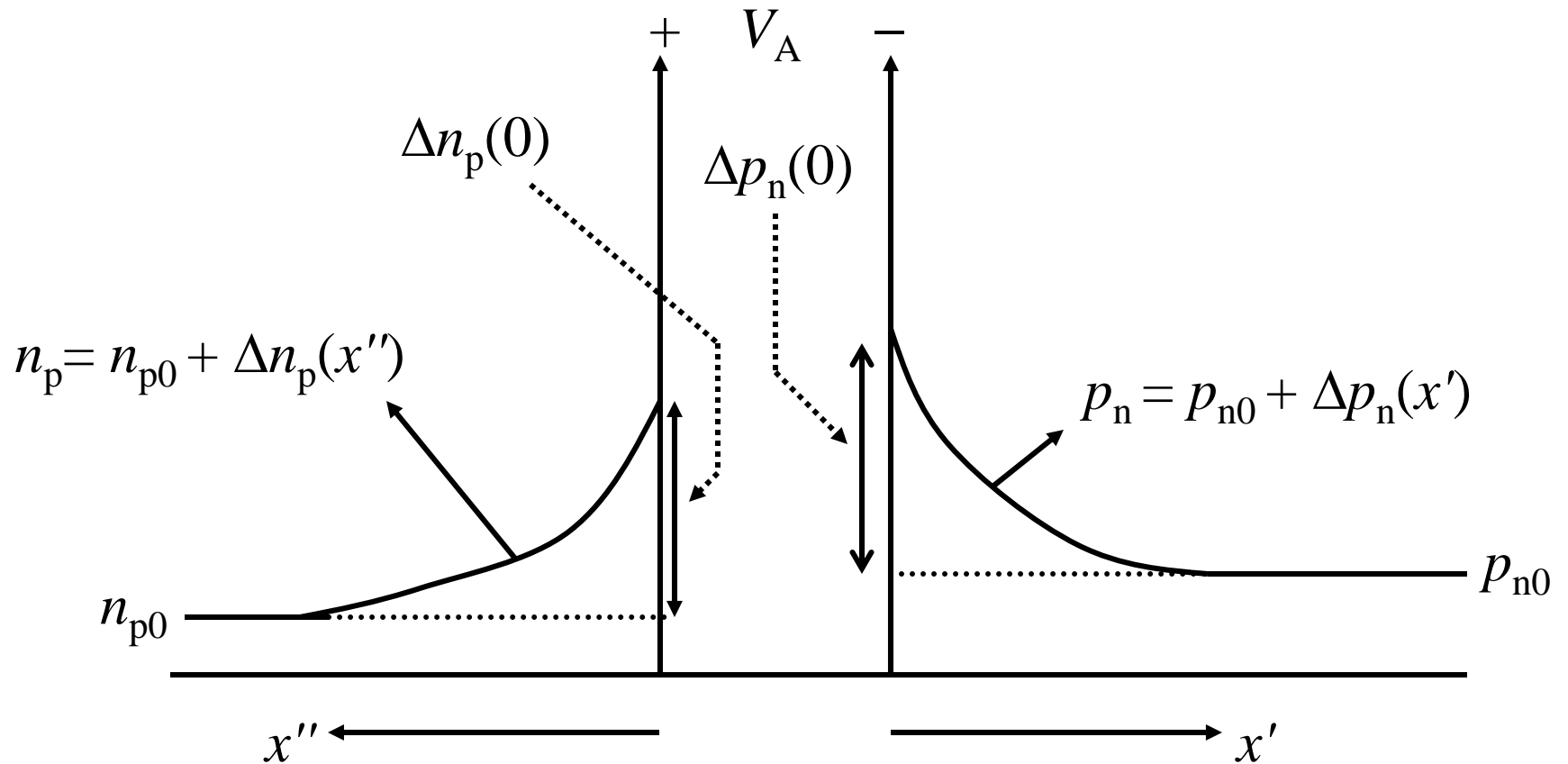
$$p_n(x_n) = p_{n0} e^{\frac{qV_A}{kT}}$$

$$\Delta p_n(x_n) = p_n(x_n) - p_{n0} = p_{n0} (e^{\frac{qV_A}{kT}} - 1)$$

Similarly,

$$\Delta n_p(-x_p) = n_{p0} (e^{\frac{qV_A}{kT}} - 1)$$

Minority carrier concentration profile under bias



$$\Delta n_p(x'') = \Delta n_p(0) e^{-\frac{x''}{L_n}}$$

$$\Delta p_n(x') = \Delta p_n(0) e^{-\frac{x'}{L_p}}$$

Carrier injection under forward bias (continued)

Change of axes to x' and x'' (see graph)

x'' axis

$$\Delta n_p(0) = n_{p0} \left(e^{\frac{qV_A}{kT}} - 1 \right)$$

$$\Delta n_p(x'') = \Delta n_p(0) e^{-\frac{x''}{L_n}}$$

$$= n_{p0} \left(e^{\frac{qV_A}{kT}} - 1 \right) e^{-\frac{x''}{L_n}}$$

x' axis

$$\Delta p_n(0) = p_{n0} \left(e^{\frac{qV_A}{kT}} - 1 \right)$$

$$\Delta p_n(x') = \Delta p_n(0) e^{-\frac{x'}{L_p}}$$

$$= p_{n0} \left(e^{\frac{qV_A}{kT}} - 1 \right) e^{-\frac{x'}{L_p}}$$

General current and minority carrier diffusion equations

$$J_p(x) = qp\mu_p E - qD_p \frac{dp}{dx}$$

$$J_n(x) = qn\mu_n E + qD_n \frac{dn}{dx}$$

$$\frac{\partial \Delta p}{\partial t} = D_p \frac{\partial^2 \Delta p}{\partial x^2} - \frac{\Delta p}{\tau_p} + G_L$$

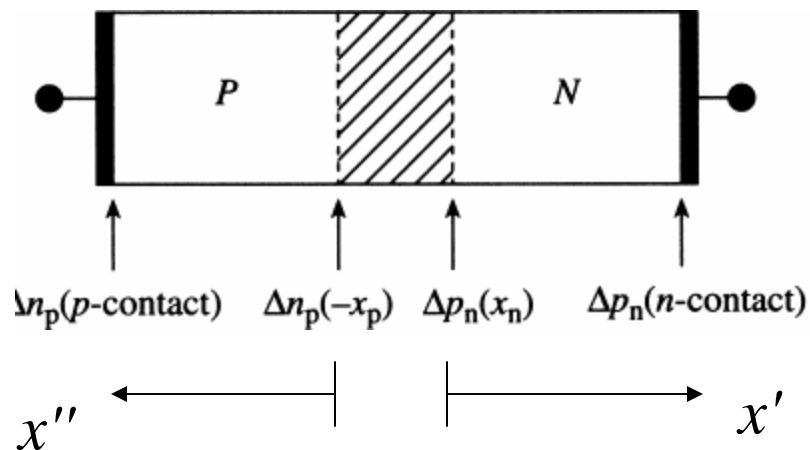
$$\frac{\partial \Delta n}{\partial t} = D_n \frac{\partial^2 \Delta n}{\partial x^2} - \frac{\Delta n}{\tau_n} + G_L$$

Simplified equations

$$J_p(x) = -qD_p \frac{dp}{dx}$$

$$0 = D_p \frac{\partial^2 \Delta p}{\partial x^2} - \frac{\Delta p}{\tau_p}$$

Current equations applied to a diode



$$J_n(x'') = qD_n \frac{d\Delta n}{dx''}$$

$$J_p(x') = -qD_p \frac{d\Delta p}{dx'}$$

Find J_n and J_p at the edge of the depletion layer and add them to get the total current.

Assumption: No generation or recombination inside the depletion layer.

Current equations applied to a diode

$$\begin{aligned} J_p &= -qD_p \frac{d}{dx'} p_n \\ &= -qD_p \frac{d}{dx'} \left[p_{n0} + \Delta p_n(0) e^{-x'/L_p} \right] \\ &= +q \left(\frac{D_p}{L_p} \right) \Delta p_n(0) e^{-x'/L_p} \end{aligned}$$

Therefore,

$$J_p(x'=0) = \left(\frac{qD_p}{L_p} \right) \Delta p_n(0) = \left(\frac{qD_p}{L_p} \right) p_{n0} \left(e^{\frac{qV_A}{kT}} - 1 \right)$$

Diode current equations

$$\text{Similarly, } J_n(x''=0) = -\left(\frac{qD_n}{L_n}\right) n_{p0} \left(e^{\frac{qV_A}{kT}} - 1\right)$$

Current due to electrons will be along positive x' direction.

And total current equals,

$$J = \left(\frac{qD_p}{L_p} p_{n0} + \frac{qD_n}{L_n} n_{p0}\right) \left(e^{\frac{qV_A}{kT}} - 1\right) \quad \text{Shockley equation}$$

$$J = J_0 \left(e^{\frac{qV_A}{kT}} - 1\right)$$

Forward and reverse bias characteristics

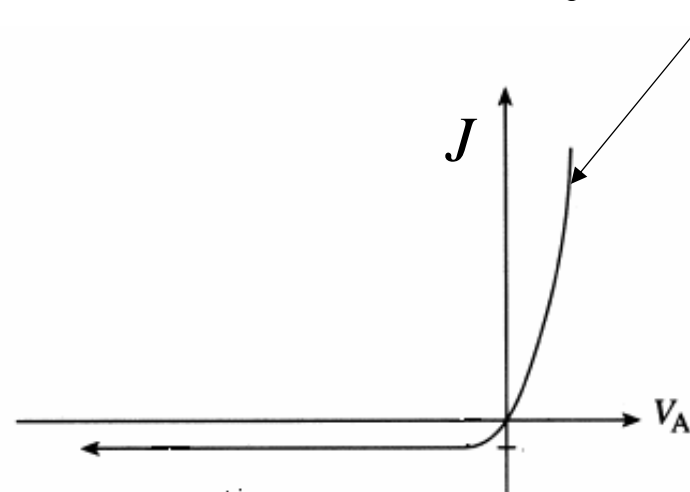
Large forward bias ($V_A \gg kT/q$):

$$J = J_0 e^{\frac{qV_A}{kT}}$$

Large reverse bias ($V_A \ll -kT/q$):

$$J = -J_0$$

$$J = J_0 (e^{\frac{qV_A}{kT}} - 1)$$



Example 1

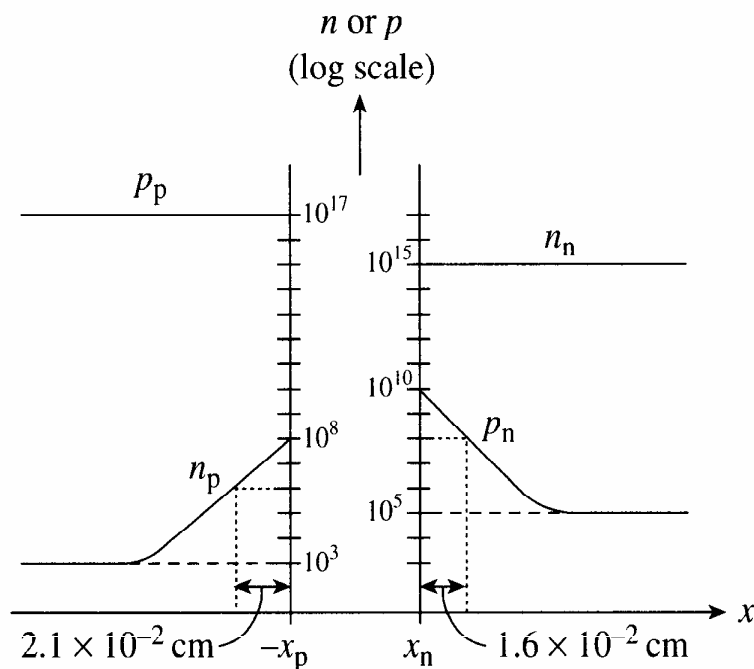


Figure E6.3

Figure 6.3 is a dimensioned plot of the steady state carrier concentration inside a pn junction diode maintained at room temperature.

- Is the diode forward or reverse biased? Explain
- Do low-level injection conditions prevail in the quasi-neutral region of the diode? Explain
- Determine the applied voltage, V_A
- Determine the hole diffusion length, L_p